Search Notes

Application/Control No.	lo. Applicant(s)/Patent under Reexamination	
10/770,295	CHANG ET AL.	
Examiner	Art Unit	
Emeka Ebirim	2166	

SEARCHED					
Class	Subclass	Date	Examiner		
707	1-10	7/7/2006	EE		
715	501.1	7/7/2006	EE		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Search	7/7/2006	EE		
Consulted Pham Khanh (primary)	7/7/2006	EE		